


<b>Search Notes</b>  	<b>Application/Control No.</b>  10600317	<b>Applicant(s)/Patent Under Reexamination</b>  CRAGUN ET AL.
	<b>Examiner</b>  SHEW-FEN LIN	<b>Art Unit</b>  2166

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
East text search	2/11/08-2/13/08	SFL
NPL (google)	2/13/08	SFL
East text search	8/11/08	SFL
East text search	6/23/09	SFL
NPL (google, ACM, IEEE)	6/23/09	SFL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
707	9	6/23/09	SFL
715	230	6/23/09	SFL

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